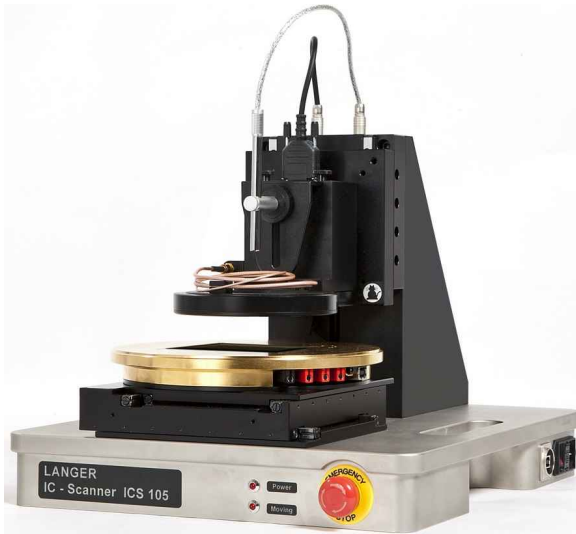


ICS 105 set

IC Scanner 4-Axis Positioning System



Short description

The ICS 105 IC scanner allows for measurements of high-frequency near fields above ICs. Depending on the used ICR near-field microprobe magnetic or electric fields can be measured with a measuring resolution of 50 to 100 μm . The probe can also be automatically rotated to determine the magnetic field's direction.

Optionally the ICS 105 scanner can be used for measurements above small assemblies in combination with UH-DUT universal holder and SH 01 probe holder.

The IC scanner can be set up for ESD or EFT immunity tests on ICs in a few simple steps.

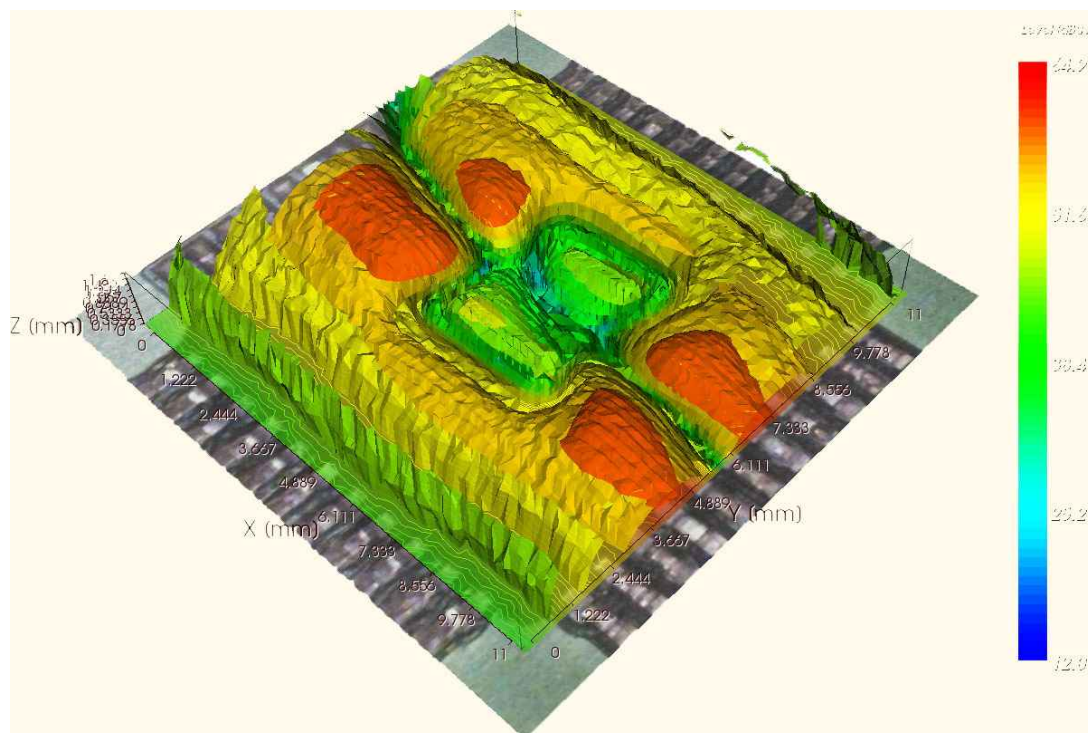
Scope of delivery

- 1x ICS 105, 4-Axis Positioning System
- 1x CS-Scanner, ChipScan-Scanner Software / USB
- 1x GND 25, Ground Plane
- 1x UH DUT set, Universal Holder for Langer scanner
- 1x DM-CAM, Digital Microscope Camera
- 1x SH 01, Probe Holder for Langer scanner
- 1x ICS Flight case, ICS Flight Case
- 1x ICS 105 m, ICS 105 User Manual

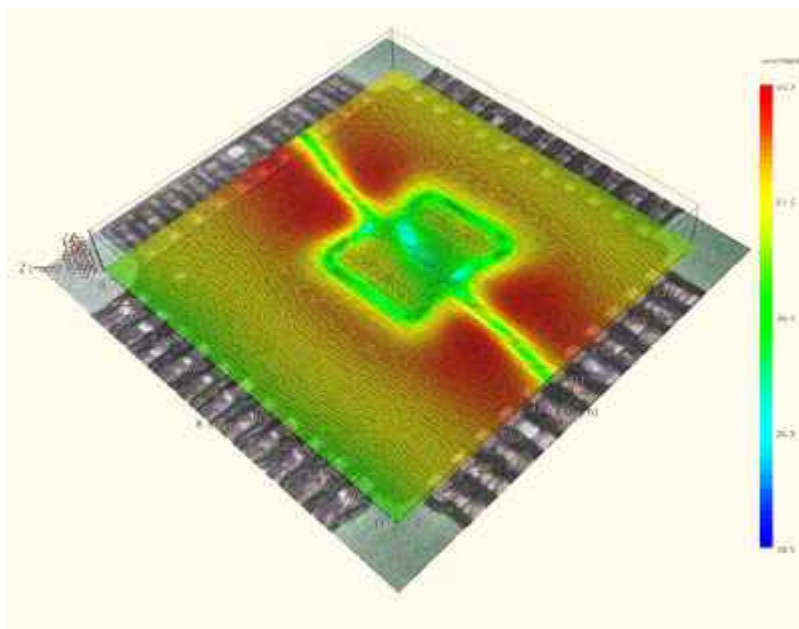
Technical parameters

Supply voltage	110 / 230 V
Interface	USB
Max. traverse range	(50 x 50 x 50) mm; α -Rotation $\pm 180^\circ$
Min. step size	(10 x 10 x 10) μm ; α -Rotation 1°
Positioning speed	(10 x 10 x 5) mm/s; α -Rotation 90°/s
Weight	23 kg
Sizes (L x W x H)	(350 x 400 x 420) mm

3D scan



Surface scan



The diagram illustrates the ICS 105 system setup. A central unit, labeled "ICS 105", is connected to a "Spectrum analyser" (left), a "Microscope camera" (top), and a "PC with ChipScan-Scanner software" (right). The "Spectrum analyser" is connected to a "GND 25 ground plane". The "Microscope camera" is connected to the "ICS 105" and a "Video transmission of the scan". The "PC" is connected to the "ICS 105" and displays the "IC scan" results on its screen. The "PC" also controls the "Spectrum analyser" and the "Scanner".

ICS 105 set

IC Scanner 4-Axis Positioning System

ICS 105 with UH DUT universal holder



ICS 105 set with UH DUT universal holder and device under test

